


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/711,633	BAKIR ET AL.	
	Examiner	Art Unit	
	Sun J. Lin	2825	

SEARCHED			
Class	Subclass	Date	Examiner
716	2	2/7/2006	JSL
716	8	2/7/2006	JSL
716	9	2/7/2006	JSL
716	10	2/7/2006	JSL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
716	2	2/7/2006	JSL
716	8	2/7/2006	JSL
716	9,10	2/7/2006	JSL

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST [USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB]	2/7/2006	JSL
IEEE	2/7/2006	JSL
GOOGLE	2/7/2006	JSL